



EV026157368

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3/25/02

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/332,271
Filing Date June 11, 1999
Inventor Klaus Florian Schuegraf et al.
Assignee Micron Technology, Inc.
Group Art Unit 2812
Examiner Ron E. Pompey
Attorney's Docket No. MI22-532
Title: Methods for Forming Wordlines, Transistor Gates, and Conductive Interconnects, and Wordline, Transistor Gate, and Conductive Interconnect Structures

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether any of the submitted references is prior art. Copies of the references are attached.

Respectfully Submitted:

Dated: 3-13-02

D. Brent Kenady
Reg. No. 40,045

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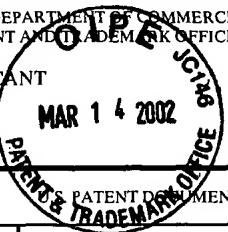
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-532	SERIAL NO. 09/332,271		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Klaus Florian Schuegraf			
				FILING DATE June 11, 1999	GROUP 2812		
U.S. PATENT DOCUMENTS TRADEMARK OFFICE							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,354,309	10/1982	Gardiner et al.			
	AB	4,559,091	12/1985	Allen et al.	148	174	
	AC	4,886,765	12/1989	Chen et al.	437	200	
	AD	5,192,708	03/1993	Beyer et al.	437	90	
	AE	5,393,676	02/1995	Anjum et al.	437	24	
	AF	5,712,181	01/1998	Byun et al.	437	46	
	AG	5,798,296	08/1998	Fazan et al.	438	592	
	AH	5,811,343	09/1998	Wann et al.	438	305	
	AI	5,985,720	11/1999	Saitoh	438	266	
	AJ	6,040,238	03/2000	Yang et al.	438	592	
	AK	5,164,333	11/1992	Schwalke et al.	437	200	
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AM	JP 02265248 A	04/1989	Japan - Kuriyama, Hiroko			Yes
	AN						No
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER				DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTN. CKET NO. M122-532	SERIAL NO. Unknown		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Klaus Florian Schuegraf et al.			
				FILING DATE Filed herewith	GROUP Unknown		
U.S. PATENT & TRADEMARK OFFICE							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,425,392	06/95	Thakur et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AL						Yes No
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AK		Taishi Kubota et al.; "The Effect of the Floating Gate/Tunnel SiO ₂ Interface on FLASH Memory Data Retention Reliability"; 1994; 2 pages				
	AL		Shoue Jen Wang et al.; "Effects of Poly Depletion on the Estimate of Thin Dielectric Lifetime"; IEEE Electron Device Letters, Vol. 12, No. 11, November 1991; pp. 617-619				
	AM		Klaus F. Schuegraf et al.; "Impact of Polysilicon Depletion in Thin Oxide MOS Technology"; 1993; pp. 86-88				
	AN		E. H. Snow et al.; "Polarization Phenomena and Other Properties of Phosphosilicate Glass Films on Silicon"; Journal of the Electrochemical Society, March 1966; pp. 263-269				
EXAMINER				DATE CONSIDERED			
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							

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				FILING DATE June 11, 1999	GROUP 2812		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,350,698	09/1994	Huang et al.	437	26	
	AB	5,441,904	08/1995	Kim et al.	437	40	
	AC	5,481,128	01/1996	Hong	257	320	
	AD	6,060,741	05/2000	Huang	257	315	
	AE	6,208,004 B1	03/2001	Cunningham	257	413	
	AF	6,239,458 B1	05/2001	Liaw et al.	257	296	
	AG	5,767,004	06/98	Balasubramanian et al.			
	AH	5,840,607	11/98	Yeh et al.			
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AM						No
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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